

Search Notes

Application/Control No.

10/724,509

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

CHAPUIS, ALAIN

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	225		
	237		
	242		
	244		
	246		
	284		
	285		
	288		
327	157		
	158		
	161		
163	6/05	gjt	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
323	246		
	284		
327	161	6/05	gjt